



# RAM Mounts Testing Summary

## GDS® Tough-Dock™ for Tab Active4 Pro & Tab Active Pro

### Products Covered\*

RAM-GDS-DOCKB-SAM54NU  
 RAM-GDS-DOCKF-SAM54NCU  
 RAM-GDS-DOCKLF-SAM54NCPU  
 RAM-GDS-DOCKLF-SAM54NCU  
 RAM-GDS-DOCKL-SAM54CD2-101U  
 RAM-GDS-DOCKL-SAM54CD2U  
 RAM-GDS-DOCKL-SAM54NCD2-101U  
 RAM-GDS-DOCKL-SAM54NCD2U  
 RAM-GDS-DOCKL-SAM54NCPU  
 RAM-GDS-DOCKL-SAM54NCU  
 RAM-GDS-DOCK-SAM54NC-CU  
 RAM-GDS-DOCK-SAM54NCD2U  
 RAM-GDS-DOCK-SAM54NCPU  
 RAM-GDS-DOCK-SAM54NCU  
 RAM-GDS-DOCK-SAM54N-MMU

### Accompanying Power Supplies

RAM-GDS-CHARGE-V3C-2U  
 RAM-GDS-CHARGE-V7CU



\*Products Covered use GDS-POGO-V1HDR (Round Tip Pogo Pins)

Test	Description
<b>Vibration – operational</b>	MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
<b>Functional Shock - operational</b>	MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth.
<b>Pogo Pins – Cycle rating</b>	Pogo pins rated to 100k cycles
<b>USB Validation Protocol, Speed, Power</b>	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
<b>Power Supply Input Voltage Tolerance</b>	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
<b>Power Supply Output Voltage Tolerance</b>	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
<b>Power Supply Load Test</b>	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
<b>Regulatory Compliance</b>	FCC, IC CE, RoHS, WEEE
<b>Safety, Emission, Immunity (Ram Power Supply)</b>	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark